TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type ( $\pi$ - MOSIV)

# 2SK3878

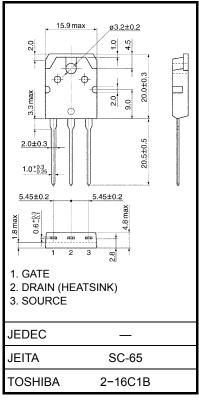
### **Switching Regulator Applications**

Unit: mm

- Low drain-source ON resistance: RDS (ON) = 1.0  $\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 7.0 \text{ S (typ.)}$
- Low leakage current:  $I_{DSS} = 100 \mu A (max) (V_{DS} = 720 V)$
- Enhancement model:  $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristic			Symbol	Rating	Unit
Drain-source voltage			$V_{DSS}$	900	V
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )			$V_{DGR}$	900	V
Gate-source voltage			V <sub>GSS</sub>	±30	V
Drain current	DC (Note	1)	I <sub>D</sub>	9	А
	Pulse (Note	1)	I <sub>DP</sub>	27	A
Drain power dissipation (Tc = 25°C)			P <sub>D</sub>	150	W
Single pulse avalanche energy (Note 2)			E <sub>AS</sub>	778	mJ
Avalanche current			I <sub>AR</sub>	9	Α
Repetitive avalanche energy (Note 3)			E <sub>AR</sub>	15	mJ
Channel temperature			T <sub>ch</sub>	150	°C
Storage temperature range			T <sub>stg</sub>	-55~150	°C



Weight: 4.6 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

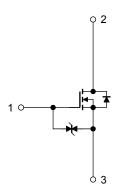
Characteristic	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	0.833	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	50	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C during use of the device.

Note 2:  $V_{DD} = 90 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$ , L = 17.6 mH,  $R_G = 25 \Omega$ ,  $I_{AR} = 9 \text{ A}$ 

Note 3: Repetitive rating: pulse width limited by max junction temperature

This transistor is an electrostatic-sensitive device. Handle with care.



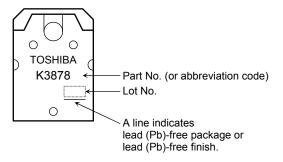
# **Electrical Characteristics (Ta = 25°C)**

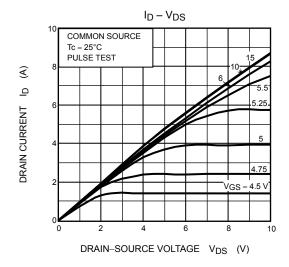
Chara	acteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	$V_{GS}=\pm30~V,~V_{DS}=0~V$	_	_	±10	μА
Drain-source breakdown voltage		V (BR) GSS	$I_G=\pm 10~\mu A,~V_{DS}=0~V$	±30	_	_	V
Drain cutoff current		I <sub>DSS</sub>	V <sub>DS</sub> = 720 V, V <sub>GS</sub> = 0 V	_	_	100	μА
Drain-source breakdown voltage V		V (BR) DSS	$I_D = 10$ mA, $V_{GS} = 0$ V	900	_	_	V
Gate threshold voltage		V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source ON resistance		R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4 A	_	1.0	1.3	Ω
Forward transfer admittance $ Y_{fS} $ $V_{DS} = 15 \text{ V}, I_D = 4 \text{ A}$		V <sub>DS</sub> = 15 V, I <sub>D</sub> = 4 A	3.5	7.0	_	S	
Input capacitance		C <sub>iss</sub>		_	2200	_	pF
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	45	_	
Output capacitance		C <sub>oss</sub>		_	190	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS} = 4 \text{ A} \text{ OVOUT}$ $V_{GS} = 100 \Omega$ $V_{DD} \approx 400 \text{ V}$ $V_{DD} \approx 400 \text{ V}$ $V_{DD} \approx 400 \text{ V}$	_	25	_	ns
	Turn-on time	t <sub>on</sub>		_	65	_	
	Fall time	t <sub>f</sub>		_	20		
	Turn-off time	t <sub>off</sub>		_	120		
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 9 \text{ A}$	_	60	_	nC
Gate-source charge		$Q_{gs}$		_	34	_	
Gate-drain ("Miller") charge		Q <sub>gd</sub>		_	26	_	

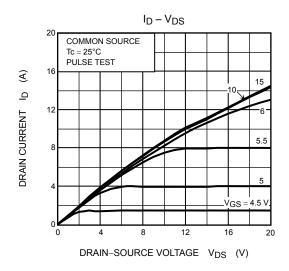
# **Source-Drain Ratings and Characteristics (Ta = 25°C)**

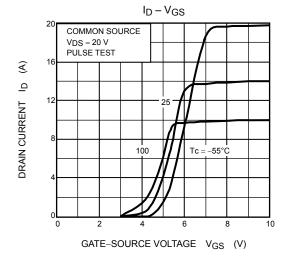
Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	9	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	27	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 9 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 9 A, V <sub>GS</sub> = 0 V,	_	1.4	_	μS
Reverse recovery charge	Q <sub>rr</sub>	dI <sub>DR</sub> /dt = 100 A/μs	_	16	_	μС

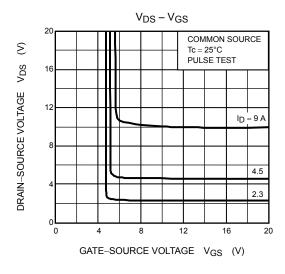
# Marking

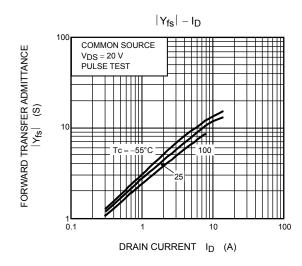


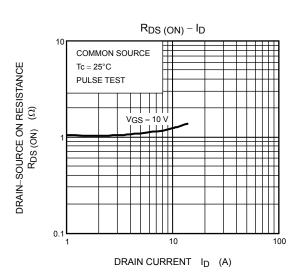




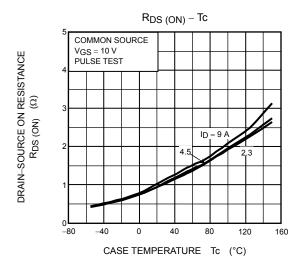


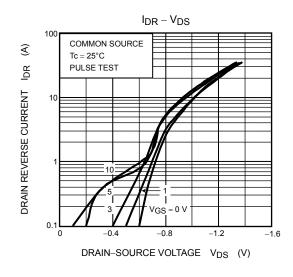


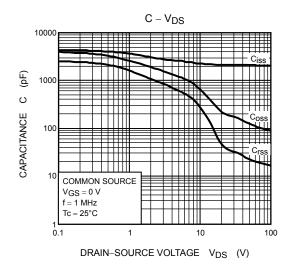


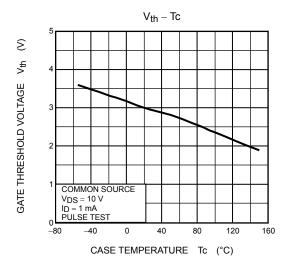


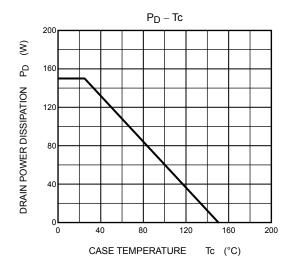
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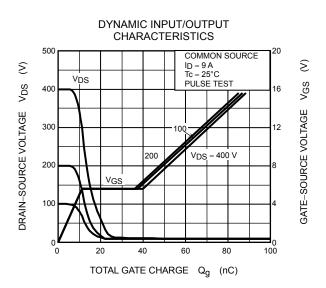


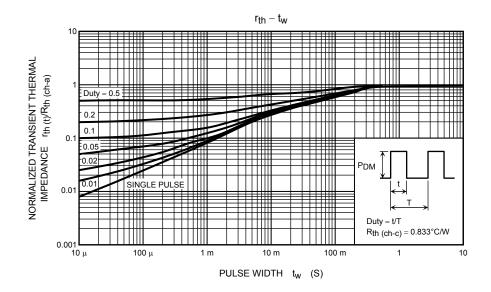


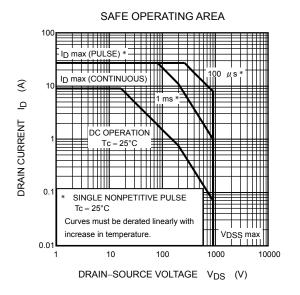


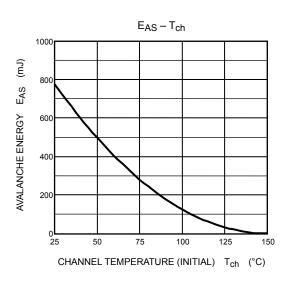


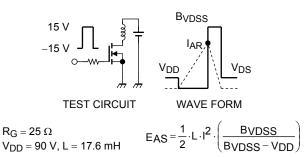












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